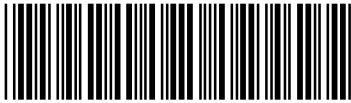


**Search Notes**

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Examiner

Andrew Lee

Applicant(s)/Patent under  
Reexamination

LEAHY ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See EAST		4/23/2008	AL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and Interference Search See EAST	4/23/2008	AL